

Heavy Ion Laboratory at University of Warsaw for the FAZIA collaboration - new ideas.

Paweł J. Napiorkowski

Heavy Ion Laboratory at University of Warsaw





Anniversary

Warsaw, 8th of April 2024

🗩 HIL

For visitors

Cooperation with the IMP

Chinese

Academy of Sciences

On July 12, 2024, we had the pleasure of hosting a delegation from China, including Prof. Enge

O

read more

YEARS

at the University of Warsaw

Basic Training

School on

BTS24

On June 18-27 2024, the

tional Basic Trai

Accelerators

tors (BTS24)

Cooperation

On June 25, 2024 we hosted a

Kazakhstan

with the INP from Almaty in

delegation from the Institute of Nuclear Physics from Almaty in

n. Director Gen

Home Page Contact

About Laborator

HIL Council Staff and PhD Studen

PAC



YEARS



Visiting laborat v imieniu własnym oraz c ręce Pana Dyrektora serdeczne y jonów z Warszawskiego Cyklotronu. Od wielu lat grupy eksp o wyspecjalizowaną aparaturę Środowisk otwartości, wiedzy i zaangażowaniu ro badawczymi w kraju i za granicą. Pows naukowe oraz organizowane przez Państw

dla studentów ciesza się uz

UNIWERS

WARSZAW

prof. dr hab. Alojzy

Rekto



Szanowny Pan Dr Paweł Napiorkowski Dyrektor Środowiskowego Laboratorium Ciężkich Jonów Uniwersytetu Warszawskiego

Kraków, 5 kwietnia 2024 r.

AE PORT

viętuje w tych dniach kierowane przez Pana nów Uniwersytetu Warszawskiego, proszę ekcji, Rady Naukowej, Pracowników Instytutu iskiego PAN, a w szczególności pracowników obiście. Uroczystość jest tym bliższa naszemu



Narodowe Laboratorium Cyklotronowe National Laboratory of Cyclotrons







EURO-LABS

Consortium of 34 institutions

15 research infrastructures

NLC/SLCJ: After ~3 years
 1000 beam hours (~3088 delivered)
 8 projects (done)
 40 users (paid)







YEARS UNIVERSITY OF WARSAW



* UNIVERSITY



* UNIVERSITY



* UNIVERSITY ★ OF WARSAW | ♥♥ ╹ ■ ■



* UNIVERSITY ★ OF WARSAW | ♥♥ ╹ ■ ■



* UNIVERSITY



GE PetTrace beam: protons -16.5 MeV deuterons - 8 MeV





Senior researchers: 9 Researchers: 21 *PhD Students: 3 Voluntary scientists: 3* Engeneeres: 10 Technicians: 16 Administration: 10 Service: 10

Total: 76 + 6



International projects submitted to the HIL PAC





Nuclear Reaction Studies with ICARE

- ICARE Particle Spectroscopy Chamber from IReS Strasburg, France Form 2007 at HIL.
- Scientific program:
 - barrier distributions measurements
 - reaction mechanism studies
 - novel detectors' tests



HIL122 N. S. Martorana / E. Geraci
T-INSIDE (Timing Investigation in SiC Detectors)
HIL123 B. Gnoffo
MoReNA Test (Molecular states Resolution with NarCoS)



Andrzej Kordyasz for Fazia



size: 1cmx1cm

orated contact from detector surface as an effect of heavy ion irradiation. Increase of charge collection efficiency of thin self-biased detectors manufactured by the low-temperature

2 Technology of production of thin self-biased silicon



Andrzej Kordyasz for Fazia

Recently

Radiation hardness 21 µm Si detectors on ¹⁴N beam @ 100 MeV from Warsaw Cyclotron (A.Kordyasz *et al.*, Eur. Phys. J. A (2024) **60**: 235 and to be published).

Currently

further development 21 µm Si detectors size: 1cmx1cm Eur. Phys. J. A (2024) 60:235 https://doi.org/10.1140/epja/s10050-024-01454-9 The European Physical Journal A

Special Article - New Tools and Techniques

Investigation of very high radiation hardness of 21 μm silicon self-biased detectors

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Abstract The radiation damage of 21 µm thick self-biased epitaxial ΔE detectors were tested as a function of fluence of 90 MeV ¹⁴N ions. Technology of production and technique of measurements of ΔE detectors were described. A new technique of soldering contact to thin detector is shown. In the present work the 21 μ m thick self-biased detectors marked as d4 and d5 show proper operation with the fluence about $4 \cdot 10^{15}$ ions/cm² and the fluence about $8 \cdot 10^{15}$ ions/cm², respectively. The charge collection efficiency of thin d5 ΔE detector was increased about double at fluence about 8.1015 ions/cm². The charge collection efficiency of thin d4 ΔE detector was increased about 35% at fluence about 4.10¹⁵ ions/cm² followed decrease about 70% of detector counting rate registration from fluence $9.1 \cdot 10^{15}$ ions/cm² to fluence about 5.1016 ions/cm2 due to partially removing of Al evaporated contact from detector surface as an effect of heavy ion irradiation. Increase of charge collection efficiency of thin self-biased detectors manufactured by the low-temperature

In an attempt to imprecial detector technologie or silicon carbide [2] h detectors are used to the and for laser induction fusilicon detectors were de however, our works are of con detectors [6, 7]. It see damage due to the extremthe internal built-in-field ness. Decreasing the ener the detector improves the detector thickness prevesince no heavy ions stop

2 Technology of produ



Detectors for COULEX









Radiobiology set-up





Radiobiology set-up



Controlled destruction of the PIN diode detector - open view chamber



Material irradiation

Courtesy of K.Krutul-Bitowska





Fig. 1. Fluence-dependent evolution of PIN diode dark current measured in the PIN diode detector irradiated with the ¹²C beam (a). The ²⁴¹Am alpha particle spectra obtained in different stages of the detector destruction process (b–d), collected immediately after cutting the beam flux off, compared to the spectrum collected for the final dark current saturation level (e).



Positron lifetime annihilation spectroscopy

- Positron spectroscopic annihilation is a method to study defects in the crystalline structure
- For the first time it was used to study defects that arise in silicon detectors
- Digital PALS setup: BaF₂ based detectors and APU8702 unit
- Positron source: ²²Na with activity of 1 MBq enveloped into a 5 µm Ti foil
- Spectra including 10⁶ counts were deconvoluted with lifetime code, substracting the background and the source components



collaboration:

Paweł Horodek, Krzysztof Siemek IFJ PAN, Cracow



Courtesy of K.Krutul-Bitowska



Positron lifetime annihilationspectroscopy

ACTA PHYSICA POLONICA A

Positron spectroscopic annihilation is a method to study defects in the crystalline structure

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collaboration: Furthermore. it was found that the surface Paweł Horodek, Krzysztof Siemek IFJ PAN, Cracow

Proceedings of the XIII International Conference "Ion Implantation and Other Applications of Ions and Electrons"

Radiation Resistance Studies of PIN Diode Detectors Irradiated with Heavy Ions

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Doi: 10.12693/APhysPolA.142.783

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The controlled destruction of the PIN diode detectors, SIEMENS SFH 870/F170 and SFH 871/F171, by the 35 MeV beam of the ¹²C and by 24 MeV of the ¹⁴N, respectively, was characterized using nuclear spectroscopy, the surface profile measurements, and the positron annihilation spectroscopy technique. The beam fluence was in the range of $10^{12}-10^{14}$ ions/cm². It has been shown that the fluence of 10^{12} ions/cm² of the ¹²C beam did not allow it to destroy the PIN diode detector. For this purpose, one needs the fluence of at least 4×10^{12} ions/cm² for the ¹⁴N ions beam and 2.2×10^{13} ions/cm² for the ¹²C ions one. The presence of divacancies in the irradiated sample was detected by the positron lifetimes measurements, with the fraction significantly higher for the ¹²C implanted sample. Furthermore, it was found that the surface roughness changed drastically following the implantation.

Courtesy of K.Krutul-Bitowska



Fig. 5. (Colour on-line) The results from the positron annihilation spectroscopy — the positron lifetimes observed for irradiated samples (marked in black) as a function of the fluence. Grey/red point corresponds to the reference PIN diode which was not exposed to the high-flux heavy-ion beam.

K.Krutul-Bitowska et al. Acta Physica Polonica B Proceedings Supplement 13 (2020) 861



Radiation Damaged - Let's Anneal Bake @130°C





Vacuum oven available at HIL

- Temperature 10-250°C
- Vacuum <133 Pa (1 Torr)





Summary

- HIL is European facility we use various experimental stations equipped thanks to European collaborations.
- The EURO-LABS Transnational Access programme makes the HIL a part of European Research Area; most of the HIL users are international teams nowadays
- Detector development and maintenance may be a continuation of HIL's cooperation with FAZIA





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